

polyfet rf devices

MILITARY SCREENING FOR TRANSISTORS

Reference: MIL-S-19500

MIL-STD-750

<u>SCREEN</u>	<u>METHOD</u>	<u>CONDITION</u>
High Temperature Life	1032	24Hrs@ 150°C
Thermal Shock	1051	Condition F, 20 Cycles t @ Extremes > 10 minutes.
Constant Acceleration	2006	Y Axis only, 10,000 G
Hermetic Seal - Gross Leak	1071	Test conditions A,C,D,E or F. Condition D @Temp=75 °C
High Temp Reverse Bias 1039		48 Hrs @ 150°C at 48V (28V) devices at (32)V (12V) devices at 100V (50V) devices
Final Electrical Test DC and RF	-----	Specified NLT 96Hrs after Burn-In
External Visual	2071	

Notes:

- a. gross leak temp only applies to condition D
- b. HTRB voltage is per table from method 1042.1